UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Mamoru NAKASUJI et al.

Serial No.:

10/619,192

Group Art Unit: Not yet assigned

Filed:

July 15, 2003

Examiner: Not yet assigned

Confirmation No.: 4935

For:

**ELECTRON BEAM APPARATUS** 

## INFORMATION DISCLOSURE STATEMENT PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

February 9, 2004

Sir:

The attention of the Patent and Trademark Office is hereby directed to the document listed on the attached Form PTO-1449. One copy of the document is attached.

No fee or certification is required in connection with this Information Disclosure Statement, since it is being submitted prior to the issuance of a first official action on the merits or expiration of the three month period following the filing date (or the entry of the national stage) of the above-captioned application.

The above information is presented so that the Patent and Trademark Office can, in the first instance, determine any materiality thereof to the claimed invention. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the documents cited in the attached Form PTO-1449 be made of record therein and appear on the first page of any patent to issue therefrom.

Serial No.: 10/619,192

The Commissioner is authorized to charge our Deposit Account No. 50-2866 for any fee which is deemed by the Patent and Trademark Office to be required to effect consideration of this statement.

Respectfully submitted,

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PTO-1449, 1 reference **Enclosures:** 

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PATENT TRADEMARK OFFICE

Examiner Initial AA 6,41 AB 6,59 AC 5,89	Applican Filing Da Gument No. Name PADEMAN Nogu  93,152 Naka  92,224 Naka	u.S. PATENT  c  uchi et al.  asuji et al.	T DOCUMEN  Date  06/25/2002  07/15/2003	Grou TS Class 356 438	p Art Unit: Subclass 237.4 14 310	Filing Date (If appropriate) 07/28/1999 11/02/2001 05/09/1997, See page 1 in the spec.	
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